AUTOMOTIVE GRADE

AUIRF2804S-7P

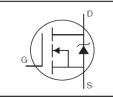
Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

HEXFET® Power MOSFET



V _{DSS}	40V
R _{DS(on)} max.	1.6m Ω
D (Silicon Limited)	320A①
D (Package Limited)	240A



G	D	S
Gate	Drain	Source

Book Bort Number Bookers Time		Standard Pack		Complete Bart Number	
Base Part Number	Package Type	Form	Quantity	Complete Part Number	
AUIRF2804S-7P	D ² Pak-7PIN	Tube	50	AUIRF2804S-7P	
AUIRF20045-7P	D Pak-/PIN	Tape and Reel Left	800	AUIRF2804S-7TRL	

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	320①	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	230	1 ,
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	240	A
I _{DM}	Pulsed Drain Current ②	1360	
P _D @T _C = 25°C	Maximum Power Dissipation	330	W
	Linear Derating Factor	2.2	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) 3	630	m l
E _{AS (tested)}	Single Pulse Avalanche Energy Tested Value ⑦	1050	- mJ
I_{AR}	Avalanche Current ②	See Fig.12a,12b,15,16	Α
E _{AR}	Repetitive Avalanche Energy ®		mJ
T_J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		0.50	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	C/VV
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount, steady state) ®		40	

HEXFET® is a registered trademark of Infineon.

2015-11-11

^{*}Qualification standards can be found at www.infineon.com



Static Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.028		V/°C	Reference to 25°C, I _D = 1.0mA
R _{DS(on)} SMD	Static Drain-to-Source On-Resistance		1.2	1.6	mΩ	$V_{GS} = 10V, I_D = 160A $ ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Transconductance	220			Ø	$V_{DS} = 10V, I_{D} = 160A$
	Drain to Course Lookens Course			20		$V_{DS} = 40V$, $V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			200	n ^	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-200	nA	$V_{GS} = -20V$

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$\overline{Q_g}$	Total Gate Charge		170	260		I _D = 160A
Q_{gs}	Gate-to-Source Charge		63		nC	$V_{DS} = 32V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		71			V _{GS} = 10V ④
t _{d(on)}	Turn-On Delay Time		17			$V_{DD} = 20V$
t _r	Rise Time		150			$I_{D} = 160A$
$t_{d(off)}$	Turn-Off Delay Time		110		ns	$R_G = 2.6\Omega$
t _f	Fall Time		100			V _{GS} = 10V ④
L _D	Internal Drain Inductance		4.5		nH	Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance		7.5		Ш	from package and center of die contact
C _{iss}	Input Capacitance		6930			$V_{GS} = 0V$
Coss	Output Capacitance		1750			$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance		970		pF	f = 1.0 MHz, See Fig. 5
C _{oss}	Output Capacitance		5740			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
C _{oss}	Output Capacitance		1570			$V_{GS} = 0V, V_{DS} = 32V, f = 1.0MHz$
C _{oss} eff.	Effective Output Capacitance 4		2340			$V_{GS} = 0V$, $V_{DS} = 0V$ to 32V

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			320①		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ②			1360		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 160A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		43	65	ns	$T_J = 25$ °C, $I_F = 160$ A, $V_{DD} = 20$ V
Q _{rr}	Reverse Recovery Charge		48	72	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrin	sic turn	on time	is neglig	ible (turn-on is dominated by L _S +L _D)

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 240A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ③ Limited by T_{Jmax}, starting T_J = 25°C, L=0.049mH, R_G = 25Ω, I_{AS} = 160A, V_{GS} =10V. Part not recommended for use above this value.
- ④ Pulse width \leq 1.0ms; duty cycle \leq 2%.
- S Coss eff. is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS.
- $\ \ \,$ Limited by T_{Jmax} , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- \odot This value determined from sample failure population, starting $T_J = 25^{\circ}C$, L = 0.049 mH, $R_G = 25\Omega$, $I_{AS} = 160 \text{A}$, $V_{GS} = 10 \text{V}$.
- This is applied to D2Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note # AN-994.
- R_θ is measured at T_J of approximately 90°C.



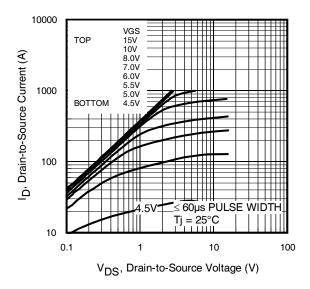


Fig. 1 Typical Output Characteristics

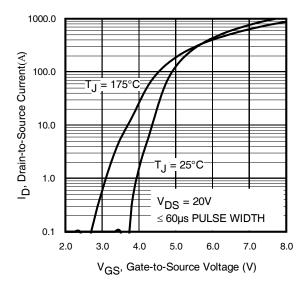


Fig. 3 Typical Transfer Characteristics

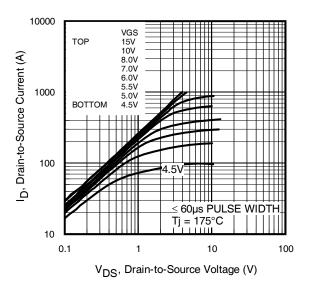


Fig. 2 Typical Output Characteristics

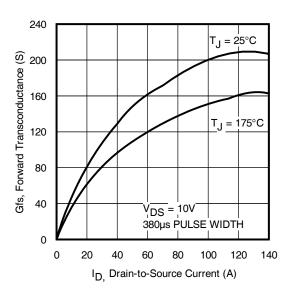


Fig. 4 Typical Forward Trans conductance vs. Drain Current



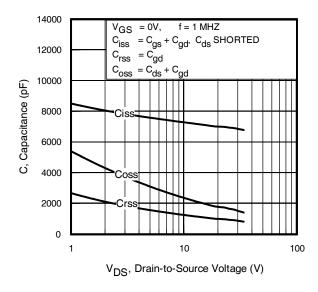


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

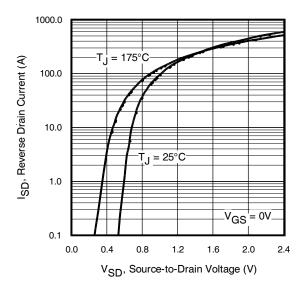


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

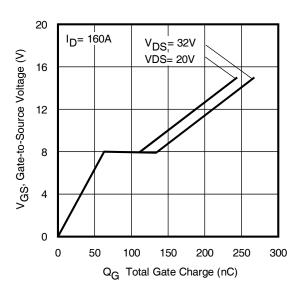


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

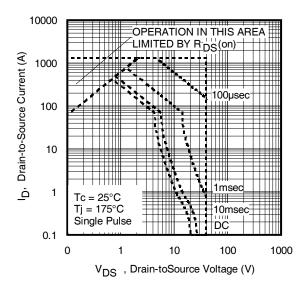


Fig 8. Maximum Safe Operating Area



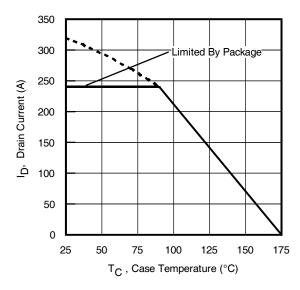


Fig 9. Maximum Drain Current vs. Case Temperature

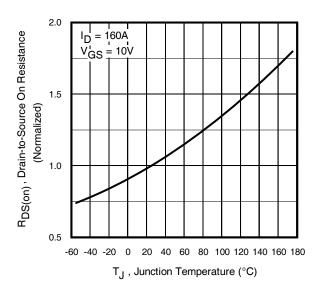


Fig 10. Normalized On-Resistance vs. Temperature

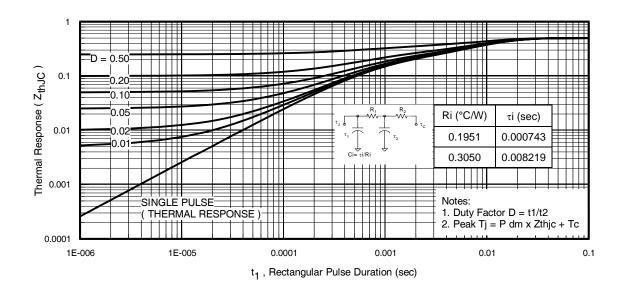


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



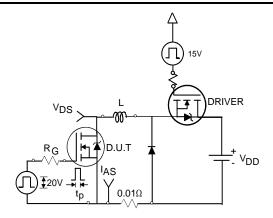


Fig 12a. Unclamped Inductive Test Circuit

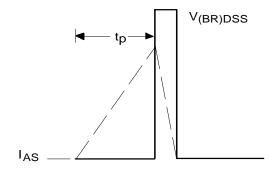


Fig 12b. Unclamped Inductive Waveforms

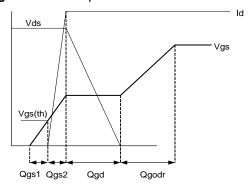


Fig 13a. Basic Gate Charge Waveform

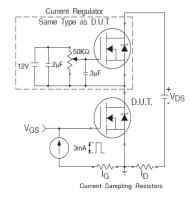


Fig 13b. Gate Charge Test Circuit

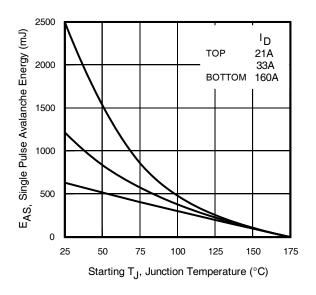


Fig 12c. Maximum Avalanche Energy vs. Drain Current

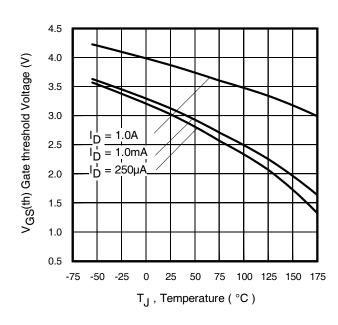


Fig 14. Threshold Voltage vs. Temperature



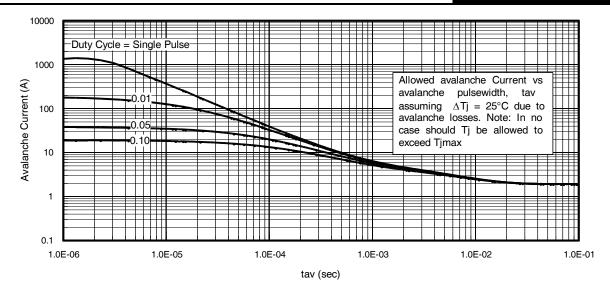


Fig 15. Typical Avalanche Current vs. Pulse width

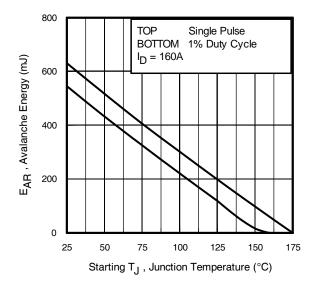


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
 - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

 $Z_{thJC}(D, tav) = Transient thermal resistance, see Figures 11)$

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



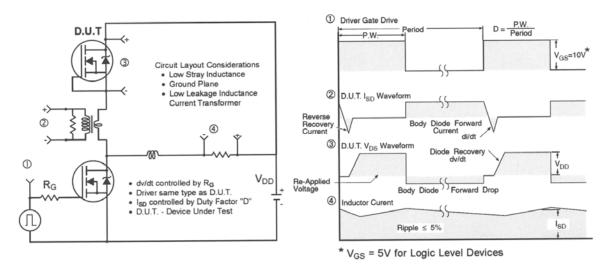


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

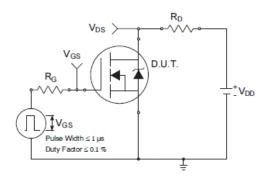


Fig 18a. Switching Time Test Circuit

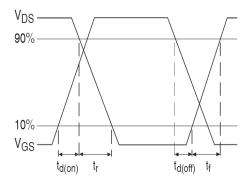
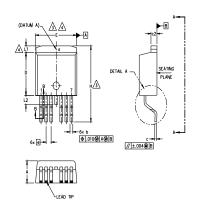


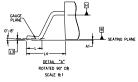
Fig 18b. Switching Time Waveforms

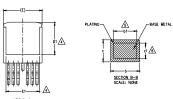


D²Pak - 7 Pin Package Outline

Dimensions are shown in millimeters (inches)





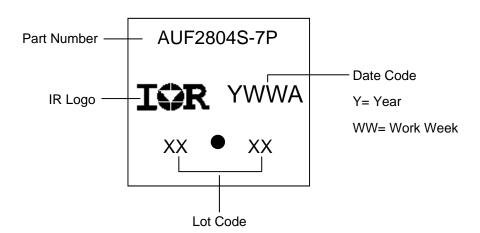


S Y M	DIMENSIONS				
BO	MILLIM	ETERS	INC	HES	NOTES
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	_	0.254	_	.010	
ь	0.51	0.99	.020	.036	
ь1	0.51	0.89	.020	.032	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	_	.270		4
E	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245		4
е	1.27	BSC	.050	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
∟1	_	1.68	_	.066	4
L2	_	1.78	_	.070	
L3	0.25	BSC	.010 BSC		
L4	4.78	5.28	.188	.208	

NOTES:

- 1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263CB.

D²Pak - 7 Pin Part Marking Information



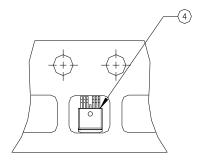
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



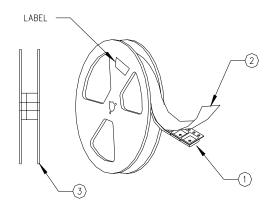
D2Pak - 7 Pin Tape and Reel

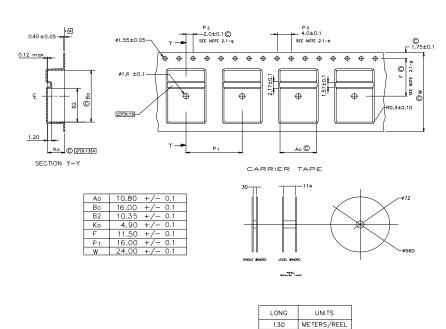
NOTES, TAPE & REEL, LABELLING:

- 1. TAPE AND REEL.
 - 1.1 REEL SIZE 13 INCH DIAMETER.
 - 1.2 EACH REEL CONTAINING 800 DEVICES.
 - 1.3 THERE SHALL BE A MINIMUM OF 42 SEALED POCKETS CONTAINED IN THE LEADER AND A MINIMUM OF 15 SEALED POCKETS IN THE TRAILER.
 - 1.4 PEEL STRENGTH MUST CONFORM TO THE SPEC. NO. 71-9667.
 - 1.5 PART ORIENTATION SHALL BE AS SHOWN BELOW.
 - 1.6 REEL MAY CONTAIN A MAXIMUM OF TWO UNIQUE LOT CODE/DATE CODE COMBINATIONS.
 REWORKED REELS MAY CONTAIN A MAXIMUM OF THREE UNIQUE LOT CODE/DATE CODE COMBINATIONS.
 HOWEVER, THE LOT CODES AND DATE CODES WITH THEIR RESPECTIVE QUANTITIES SHALL APPEAR ON THE BAR CODE LABEL FOR THE AFFECTED REEL.



- 2. LABELLING (REEL AND SHIPPING BAG).
 - 2.1 CUST. PART NUMBER (BAR CODE): IRFXXXXSTRL-7P
 - 2.2 CUST. PART NUMBER (TEXT CODE): IRFXXXXSTRL-7P
 - 2.3 I.R. PART NUMBER: IRFXXXXSTRL-7P
 - 2.4 QUANTITY:
 - 2.5 VENDOR CODE: IR
 - 2.6 LOT CODE:
 - 2.7 DATE CODE:





Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

			Automotive (per AEC-Q101)			
Qualificat	ion Level					
		D ² PAK 7 Pin MSL1				
	Machine Model	Class M4 [†]				
		(Per AEC-Q101-002)				
500	Human Body Model		Class H3A [†]			
ESD			(per AEC-Q101-001)			
	Charged Device Model	Class C5 [†] (per AEC-Q101-005)				
RoHS Cor	mpliant	Yes				

[†] Highest passing voltage.

Revision History

Date	Comments			
11/11/2015	Updated datasheet with corporate template			
11/11/2013	Corrected ordering table on page 1.			

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